

Notice of References Cited	Application/Control No. 10/642,760		Applicant(s)/Patent Under Reexamination TSUCHIYA ET AL.	
	Examiner Sheela C. Chawan		Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,173,719	12-1992	Taniguchi et al.	356/394
	B	US-6,084,716	07-2000	Sanada et al.	359/629
	C	US-6,603,875 B1	08-2003	Matsuyama et al.	382/145
	D	US-6,040,911	03-2000	Nozaki et al.	356/394
	E	US-7,127,126 B2	10-2006	Sakai et al.	382/294
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Haruo Yoda et al., " repeating pattern defect detection device", 11/01/1984 United States Patent and Trademark Office, Washington, D.C. March 2007. Pages 1-21.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.